Unit in mm

TOSHIBA GTR MODULE SILICON N CHANNEL IGBT

M G 5 0 J 1 B S 1 1

HIGH POWER SWITCHING APPLICATIONS. MOTOR CONTROL APPLICATIONS.

High Input Impedance

High Speed : $t_f = 1.0 \mu s (Max.) (I_C = 50A)$

Low Saturation Voltage : $V_{CE(sat)} = 2.7V \text{ (Max.) (I}_{C} = 50A)$

Enhancement-Mode

The Electrodes are Isolated from Case.

EQUIVALENT CIRCUIT



27 **JEDEC EIAJ** TOSHIBA 2-33F1A

Weight: 86g

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Collector-Emitter Voltage		v_{CES}	600	V	
Gate-Emitter Voltage		v_{GES}	±20	V	
Collector Current	DC	$I_{\mathbf{C}}$	50		
	1ms	I_{CP}	100	A	
Collector Power Dissipation		$P_{\mathbf{C}}$	150	W	
Junction Temperature		$T_{ m j}$	150	°C	
Storage Temperature Range		$\mathrm{T_{stg}}$	-40~125	$^{\circ}\mathrm{C}$	
Isolation Voltage		V_{Isol}	2500 (AC 1 Minute)	V	
Screw Torque (Terminal / Mounting)		_	2/3	N⋅m	

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ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I_{GES}	$V_{GE} = \pm 20V, V_{CE} = 0$	_	_	±500	nA
Collector Cut-off Current		I_{CES}	$V_{CE} = 600V, V_{GE} = 0$	_		1.0	mA
Gate-Emitter Cut-off Voltage		V _{GE(OFF)}	$I_{\text{C}} = 50 \text{mA}, V_{\text{CE}} = 5 \text{V}$	3.0	_	6.0	V
Collector-Emitter Saturation Voltage		V _{CE(sat)}	$I_{C} = 50A, V_{GE} = 15V$		2.3	2.7	V
Input Capacitance		$C_{ m ies}$	$V_{CE} = 10V, V_{GE} = 0, f = 1MHz$		3500		pF
Switching Time	Rise Time	$t_{\mathbf{r}}$	+15V -15V -15V	_	0.3	0.8	μs
	Turn-on Time	t_{on}		_	0.4	1.0	
	Fall Time	t_f		_	0.6	1.0	
	Turn-off Time	$t_{ m off}$	300V	_	1.0	1.6	
Thermal Resistance		R _{th(j-c)}	_	_	_	0.83	°C/W